

## Progress on the Low Resistance Strip Sensors and Slim Edges Combined RD50 Project

*Tuesday 4 June 2013 16:40 (20 minutes)*

A status report will be presented on the Common RD50 Project “Low Resistance Strip Sensors”. Three RD50 institutes are collaborating in this project (CNM-Barcelona, IFIC-Valencia, and SCIPP-Santa Cruz), in which a new method to enhance the sensor hardness to beam-loss damage is studied. The key feature of the method is implementation low-resistance implants. The fabrication has been combined with new experiments related to another RD50 Common Project involving Slim Edges.

Low Resistance Strip Sensors have been electrically tested. Initial IV measurements indicate that we need to modify some fabrication/design parameters in order to achieve better Punch-Through protection. We have started another fabrication batch with the improved parameters. In the meantime, we are performing a series of available tests on the new type of sensors. We will present results from the tests and an updated schedule.

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